

Receipt date: 10/26/2006

10568829 - GAU: 1796

INFORMATION DISCLOSURE CITATION

Docket No 0094.064A

Serial No.: 10/568,829

Applicant(s): Siegel et al.

Examiner: Unassigned

Filing Date: February 21, 2006

GAU: 2831

U.S. PATENT DOCUMENTS

Examiner Initial	Ref	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,228,904	5/8/2001	Yadav et al.			
	AB	6,417,265	7/9/2002	Foulger			
	AC	6,667,368	12/23/2003	Brennan et al.			

U.S. PATENT APPLICATION PUBLICATIONS

Examiner Initial	Ref	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate

FOREIGN PATENT DOCUMENTS

Examiner Initial	Ref	Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	CA	DE 4037972	06.27.1991	Germany				
	CB	WO 00/52712	08.09.2000	PCT				
	CC	WO 02/096982	05.12.2002	PCT				
	CD	WO 2004/038375	06.05.2004	PCT				
	CE	WO 2004/034409	22.04.2004	PCT				

OTHER DOCUMENTS

(Including Author, title, Date, Pertinent Pages, etc.)

	DA	Onneby et al., "Electrical Properties of Field Grading Materials Influenced by the Silicon Carbide Grain Size," <i>IEEE</i> , pp. 43-45 (2001).
	DB	Martensson et al., "Electrical Properties of Field Grading Materials with Silicon Carbide and Carbon Black," <i>IEEE</i> , pp. 548-552 (1998).

EXAMINER:

/Hui Chin/

Date Considered

12/02/2009

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH /H.C./

Sheet 1 of 1